


<b>Search Notes</b>  	<b>Application/Control No.</b>  10549752	<b>Applicant(s)/Patent Under Reexamination</b>  YANO, ATSUYOSHI
	<b>Examiner</b>  Faulk, Devona E	<b>Art Unit</b>  2615

SEARCHED			
Class	Subclass	Date	Examiner
391	98-101	2/6/2008	DEF
704	233,267,211,278,500,501,211	2/18/2008	DEF
381	98-101	7/11/08	DEF
704	233,267,211,278,500,501	7/11/08	DEF

SEARCH NOTES		
Search Notes	Date	Examiner
Assignee/inventor search	2/6/2008	DEF
word search; combined class/word search	2/6,8,13,14,18/08	DEF
additional search	7/11,13/08	DEF

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner